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Standard Guide for Analysis of Overtest Data in Radiation Testing of Electronic Parts¹

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1. Scope

1.1 This guide covers the use of overtesting in order to reduce the required number of parts that must be tested to meet a given quality acceptance standard. Overtesting is testing a sample number of parts at a stress level higher than their specification stress in order to reduce the amount of necessary data taking. This guide discusses when and how overtesting may be applied to forming probabilistic estimates for the survival of electronic piece parts subjected to radiation stress. Some knowledge of the probability distribution governing the stress-to-failure of the parts is necessary, although exact knowledge may be replaced by over-conservative estimates of this distribution.

1.2 *This international standard was developed in accordance with internationally recognized principles on standardization established in the Decision on Principles for the Development of International Standards, Guides and Recommendations issued by the World Trade Organization Technical Barriers to Trade (TBT) Committee.*

2. Referenced Documents

2.1 Military Standards:²

MIL-PRF 19500R Performance Specification: Semiconductor Devices, General Specification for, 24 July 2021

MIL-PRF 38535M Performance Specification Integrated Circuits (Microcircuits) Manufacturing, General Specification for, 1 November 2022

3. Terminology

3.1 Definitions of Terms Specific to This Standard:

3.1.1 *confidence*—the probability, C , that at least a fraction, P , of the electronic parts from a test lot will survive in actual service; since radiation testing of electronic parts is generally

destructive, this probability must be calculated from tests on selected specimens from the lot.

3.1.2 *rejection confidence*—the probability, R , that a lot will be rejected based on destructive tests of selected specimens if more than a specified fraction, P , of the parts in the lot will fail in actual service.

3.1.3 *Discussion of Preceding Terms*—Strictly speaking, most lot acceptance tests (be they testing by attributes or variables) do not guarantee survivability, but rather that inferior lots, where the survival probability of the parts is less than probability, P , will be rejected with confidence, C . In order to infer a true confidence, it would require a Bayes Theorem calculation. In many cases, the distinction between confidence and rejection confidence is of little practical importance. However, in other cases (typically when a large number of lots are rejected) the distinction between these two kinds of confidence can be significant. The formulas given in this guide apply whether one is dealing with confidence or rejection confidence.

4. Summary of Guide

4.1 This guide is intended to primarily apply to sampling by attribute plans typified by Lot Tolerance Percent Defective (LTPD) tables given in MIL-PRF 38535M and MIL-PRF 19500R, and contains the following:

4.1.1 An equation for estimating the effectiveness of overtesting in terms of increased probability of survival,

4.1.2 An equation for the required amount of overtesting given a necessary survival probability, and

4.1.3 Cautions and limitations on the method.

5. Significance and Use

5.1 Overtesting should be done when (1) testing by variables is impractical because of time and cost considerations or because the probability distribution of stress to failure cannot be estimated with sufficient accuracy, and (2) an unrealistically large number of parts would have to be tested at the specification stress for the necessary confidence and survival probability.

6. Interferences

6.1 *Probability Distributions*—In overtesting, a knowledge of the probability distribution governing stress to failure is

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² Available from Standardization Documents Order Desk, Bldg. 4 Section D, 700 Robbins Ave., Philadelphia, PA 19111-5094, Attn: NPODS.